

OVM/UVM for FPGAs: The End of Burn and Churn

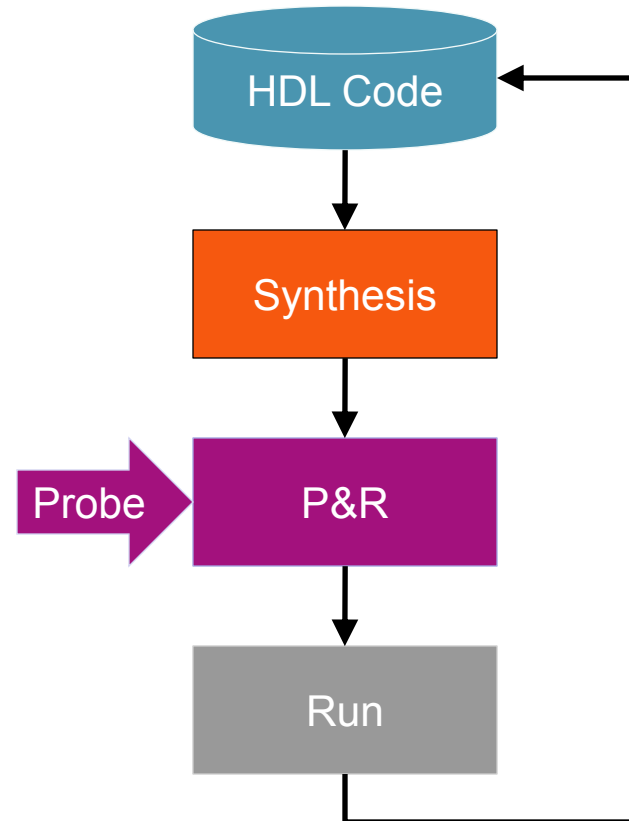


ALDEC

FPGA Verification by In-Circuit Test

“Burn and churn” based on at-speed test with real input

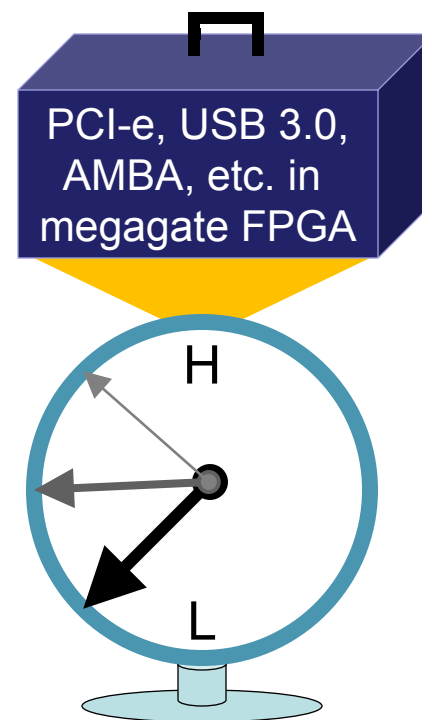
- Shortest path to the lab
 - ◆ Nominal simulation of RTL blocks
 - ◆ Relatively short synthesis/ P&R cycle with at-speed run
- Real-world verification
 - ◆ Stimulus from bench testers or actual in-circuit input
- Probes provide observability
 - ◆ Critical nodes retain during programming
 - ◆ Debug and respin



Design Requirements Pressure Methodology

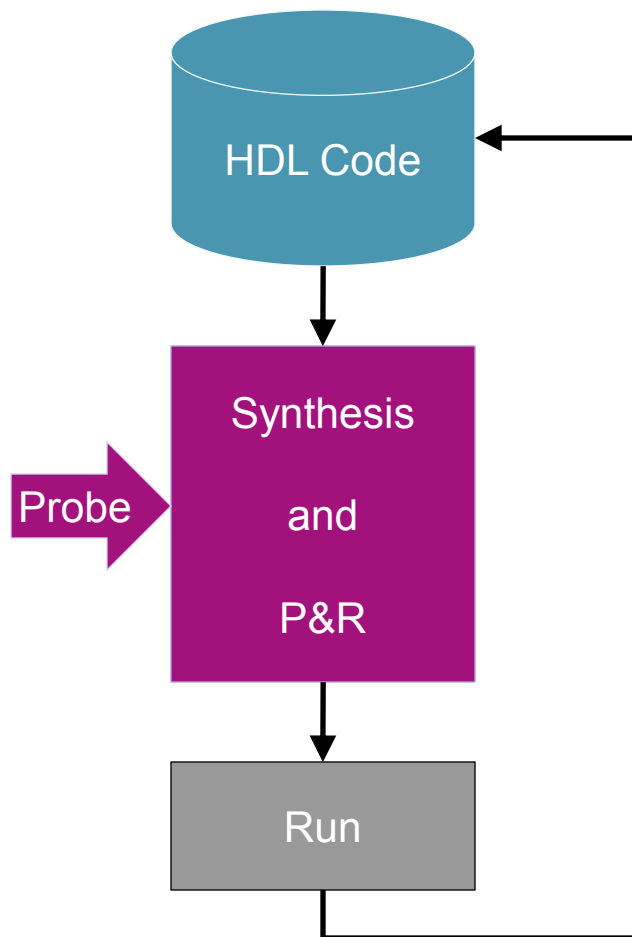
Bigger designs and more standard protocol use

- Mega-gate FPGAs depend on IP
 - ◆ Block-level verification by the vendor
 - ◆ Deep hierarchy reduces engineer's ability to know the whole design
- State-space grows exponentially
 - ◆ Increasingly difficult to create corner cases in the lab with only directed testing
- Must verify protocol interaction
 - ◆ Assuming each protocol is verified, how do they interact in the system?



Weighing Down
Observability and
Controllability

Predictability of Burn and Churn is Gone

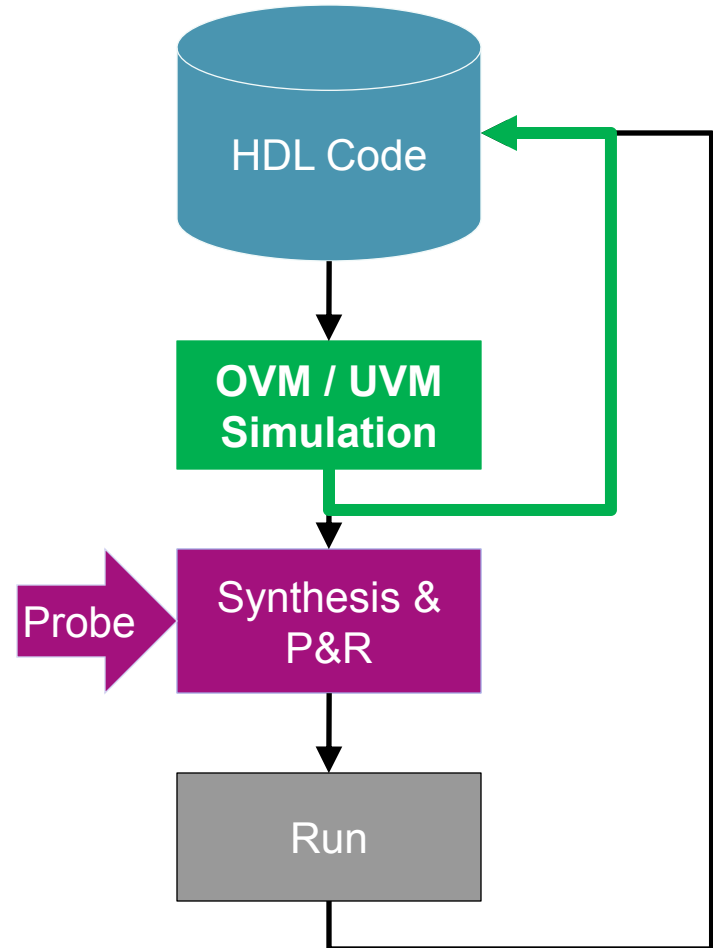


- “Burn” is now the long-pole
 - ◆ Synthesis and P&R merging due to FPGA complexity
 - ◆ “Burn” time is approaching system simulation speed
- “Run” is fast but unobservable
 - ◆ Changing probes forces new programming
 - ◆ Design too large to “know”
 - ◆ Difficult corner case testing
 - ◆ Debug becoming incremental – where is the end?

OVM/UVM Increases FPGA Verification Quality

Observability and controllability augment in-circuit

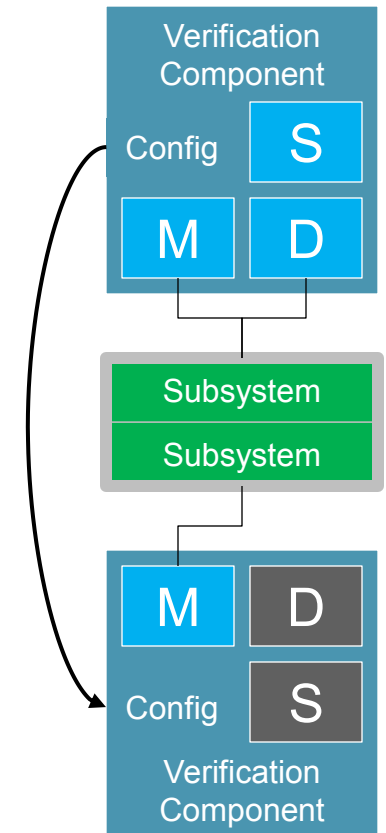
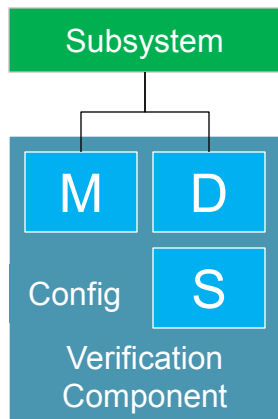
- Fully observable simulation
 - ◆ Assertions heighten observability with temporal monitoring key to complex protocols
 - ◆ Coverage measures verification progress against plan
- OVM / UVM augments in-circuit
 - ◆ Scalability via verification components from block to system
 - ◆ Controllability via virtual sequences
 - ◆ Reuse via factory localization



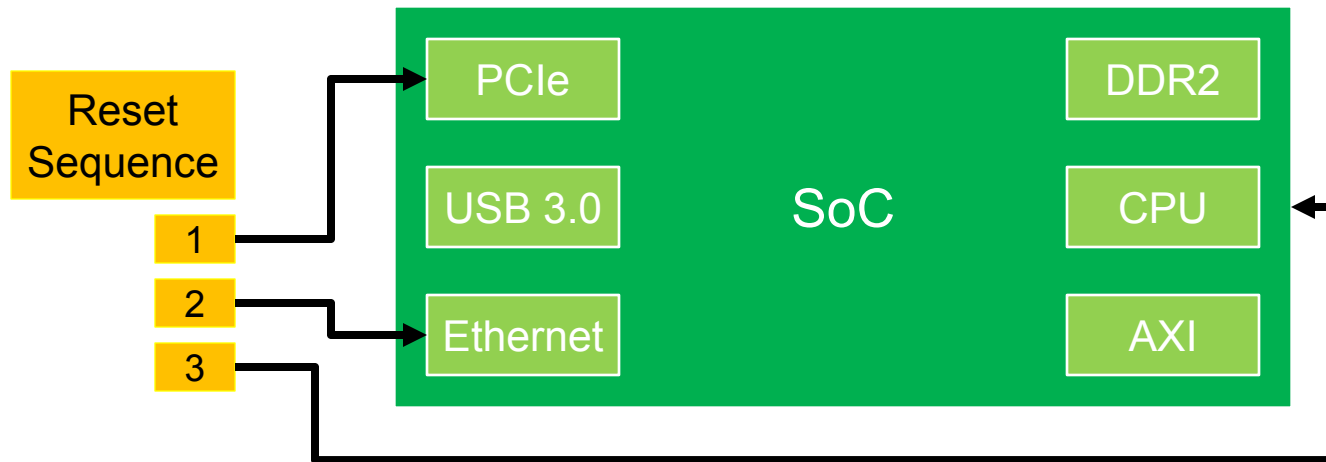
FPGA SoC is All About Rapid Assembly

OVM/UVM verification components scale with SoC

- Verification component
 - ◆ Driver, monitor, sequencer separated for modular implementation
 - ◆ Configuration lives within the component
 - ◆ Consistent TLM channel for component connection
- Rapid verification environment assembly
 - ◆ Components configure hierarchically
 - ◆ Lower-level components switch to passive
- *Reduces burn-and-churn test reconfiguration effort*



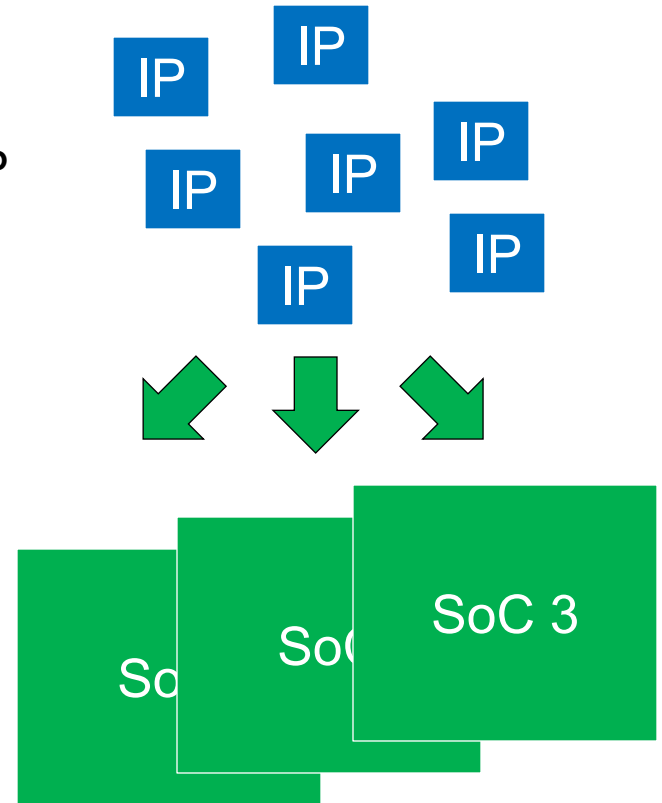
Virtual Sequences Reach Corner Cases



- Reset sequences unique to an SoC configuration
 - ◆ Virtual sequences enable rapid debug of reset
- Creating and randomizing difficult real world conditions
 - ◆ Coordinated events on multiple interfaces
 - ◆ Asynchronous activity on multiple interfaces (pushing to the limit)
- *Reduces lab time set up; going beyond limited directed tests; exhaustive testing*

Reuse, Reuse, Reuse

- FPGA engineers pull IP from many suppliers
 - ◆ OVM/UVM assures consistent verification IP for rapid integration
 - ◆ Today's top-level IP may be deeply embedded tomorrow as FPGAs grow
- FPGA architecture lends itself to rapid derivative creation
 - ◆ OVM/UVM factory enables localization without changing code
- OVM/UVM improves productivity in derivative creation and supplier interaction



FPGA Engineers: Escape Burn-and-Churn!

Learn and apply OVM/UVM

- Burn-and-churn is on the run
 - ◆ Driven by lack of observability and controllability in in-circuit FPGA testing
 - ◆ At-speed (in-circuit) tests will still be part of FPGA verification
- OVM/UVM simulation available for all FPGA engineers
 - ◆ Not just for high-end FPGA/ASIC anymore
- Multiple resources for OVM/UVM
 - ◆ OVMWorld.org and UVMWorld.org
 - ◆ Multiple training resources available
- Aldec's Riviera-PRO simulator supports
 - ◆ OVM 2.1.1
 - ◆ UVM-EA release

